

Supplementary Information

Pre-reaction suppressing strategy for α -Ga₂O₃ halide vapor pressure epitaxy using asymmetric precursor gas flow

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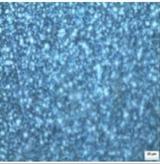
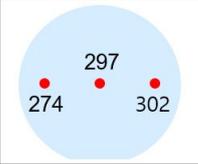
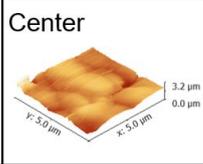
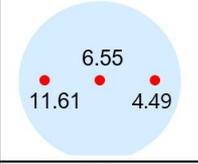
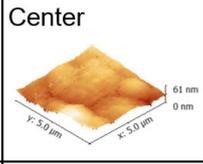
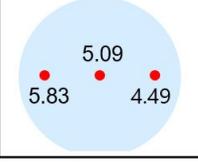
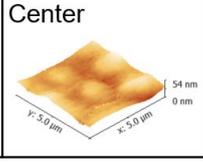
| Inner tube N ₂ (sccm) | Photo image | OM image (x500) | AFM RMS (nm) | |
|-------------------------------------|---|---|--|---|
| 1100 |  |  |  | Center  |
| 3200 |  |  |  | Center  |
| 3900 |  |  |  | Center  |

Fig. S1 Photo, OM, and AFM images showing surface morphologies of the α -Ga₂O₃ epilayer according to the inner tube N₂ carrier gas flow rate control for asymmetric gas supply to suppress pre-reaction.

Fig. S1 shows the surface morphology of the α -Ga₂O₃ epilayer according to different inner tube carrier gas flow rate in the form of photo, OM, and AFM images. At a N₂ carrier gas flow rate of 1100 sccm, pre-reaction can occur because the relatively low carrier gas flow rate provides sufficient time for the main precursors to react before reaching the substrate. As a result, Ga₂O₃ powder was deposited on the substrate, and the surface RMS value as high as 297 nm was observed. By increasing the flow rate to 3200 sccm, a large amount of powder on the surface of the 2-inch substrate disappeared; however, some powder still exist on the surface, and several pits were observed in the OM image. At the flow rate of 3900 sccm, it displayed a clean surface and low RMS value of 5.09 nm. By increasing the carrier gas, the pre-reaction was effectively suppressed.

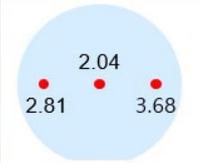
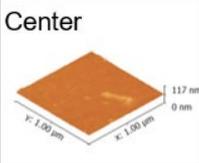
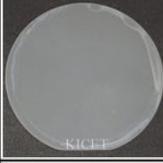
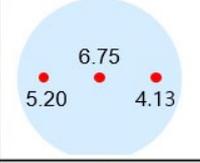
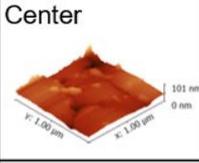
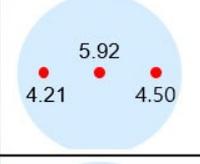
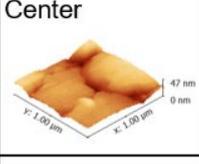
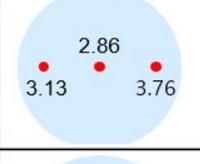
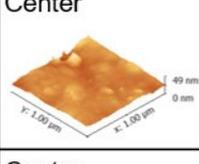
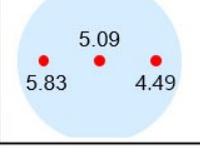
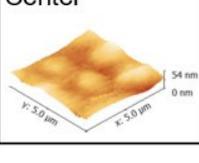
| Susceptor position (cm) | Photo image | OM image (x500) | AFM RMS (nm) | |
|-------------------------|---|---|--|---|
| 5 |  |  |  | Center  |
| 7.5 |  |  |  | Center  |
| 9 |  |  |  | Center  |
| 10 |  |  |  | Center  |
| 11 |  |  |  | Center  |

Fig. S2 Susceptor position control for uniform growth of the α -Ga₂O₃ epilayer: Photo, OM, and AFM images.

Fig. S2 shows the surface morphologies of the α -Ga₂O₃ epilayer according to different susceptor positions as photo, OM, and AFM images. The distribution of the main precursor in the substrate was controlled by adjusting the susceptor position. The difference in surface roughness according to the susceptor position was insignificant. This is the effect of suppressing the pre-reaction by optimally setting the N₂ gas flow rate.

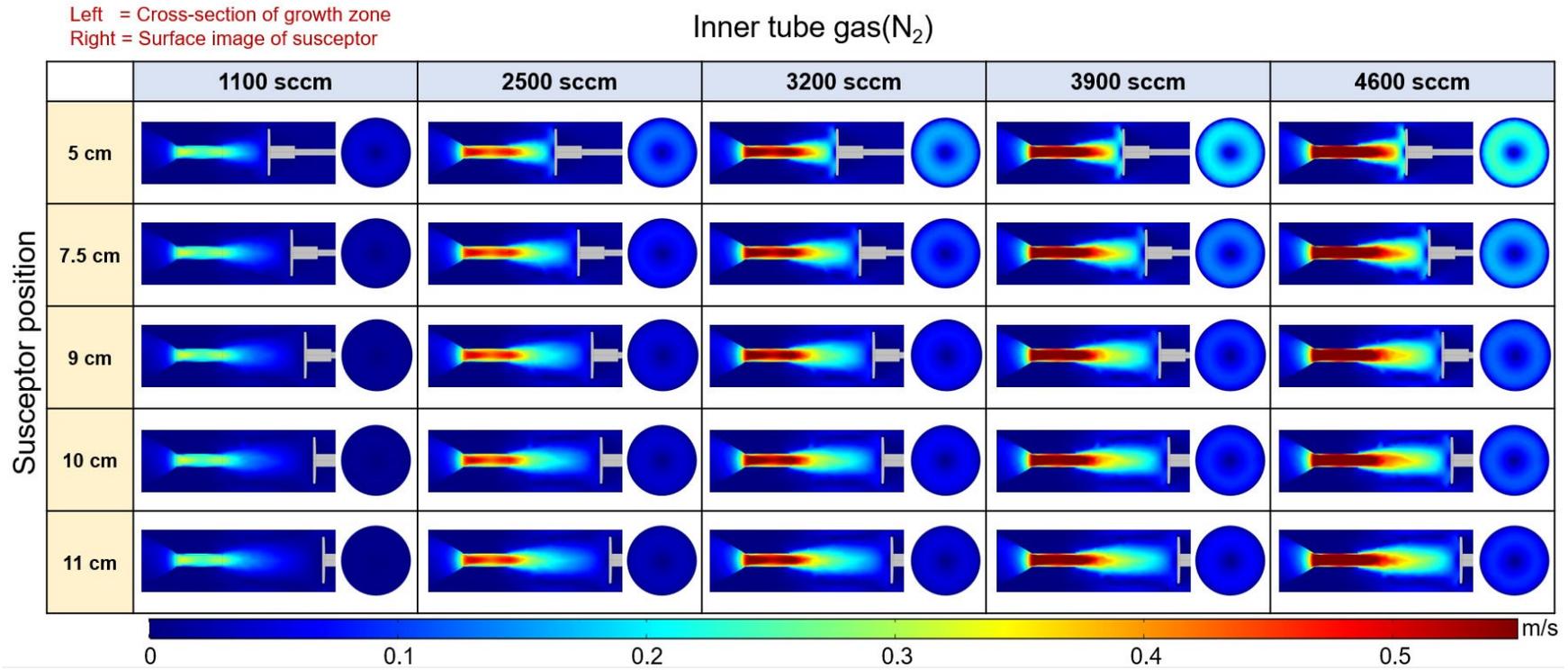


Fig. S3 Gas velocity simulation with different inner tube N₂ carrier gas flow rates and susceptor positions.

Fig. S3 displays the cross-sections of growth zone and surface images of susceptor obtained from the gas velocity simulation for the inner tube carrier gas at different flow rates of 1100–4600 sccm and different susceptor positions of 5–11 cm. To grow a uniform α -Ga₂O₃ epilayer, the gas velocity should be 0.038–0.047 m/s and the deviation should be less than 0.02 m/s.

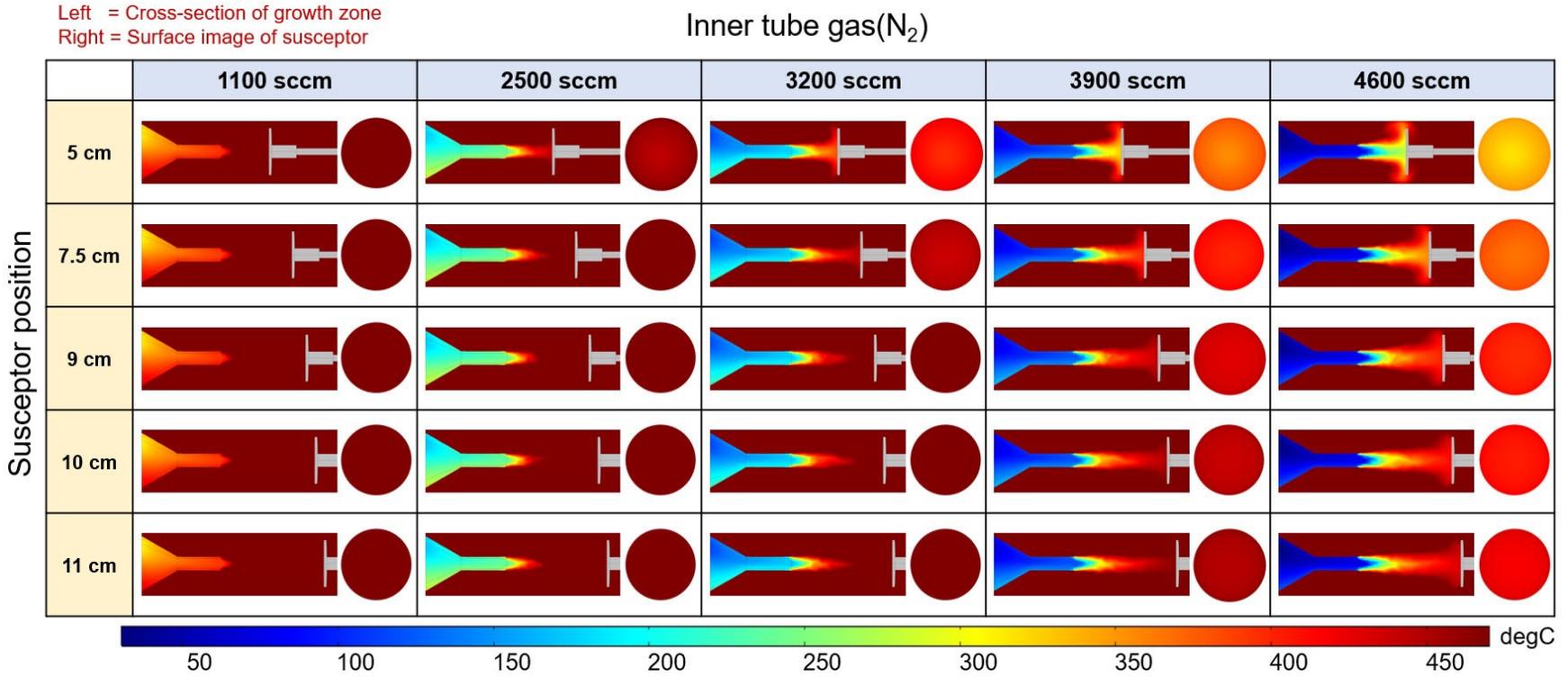


Fig. S4 Temperature simulation with different inner tube N₂ carrier gas flow rates and susceptor positions.

Fig. S4 shows the results of temperature simulation at inner tube carrier gas flow rates of 1100–4600 sccm and susceptor positions of 5–11 cm. A High-quality α -Ga₂O₃ epilayer can be grown at a gas temperature of 470 °C and a deviation of less than 1 °C.

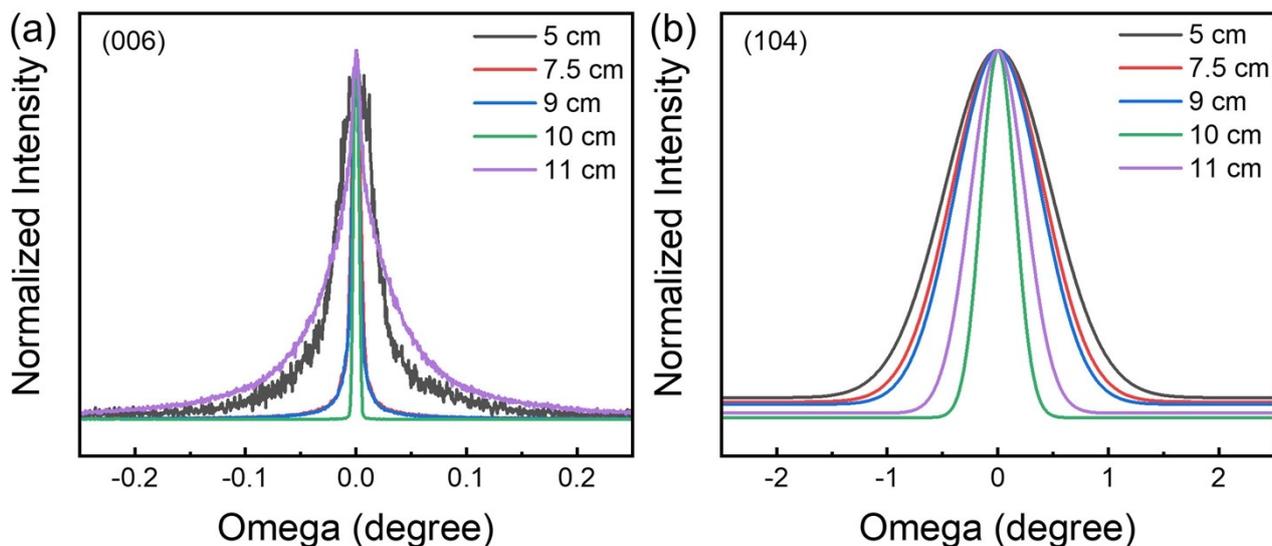


Fig. S5 X-ray omega rocking curves of the α -Ga₂O₃ epilayers grown at different susceptor positions: (a) (0006) and (b) (10-14) reflections.

Fig. S5 shows (0006) and (10-14) reflection X-ray omega rocking curves of the α -Ga₂O₃ epilayers grown at different susceptor positions ranging from 5 cm to 11 cm. At different susceptor positions, the (0006) peaks have an FWHM value of 29–155 arcsec, and the (10-14) peak has an FWHM value of 1301–4041 arcsec. FWHM increases as the susceptor position becomes shorter or longer than the proper position. The proper position means the susceptor position under optimal conditions.